Substitute for form 1449/PTO				Complete if Known		
				Application Number	10/698,822-Conf. #1260	
Sυ	PPLEMENTA	L IN	IFORMATION	Filing Date	October 30, 2003	
	DISCL	osi	JRE	First Named Inventor	Paul C. ALLEN	
l s	TATEMENT E	3Y /	APPLICANT	Art Unit	2873	
				Examiner Name	B. N. Thomas	
Sheet	1	of	1	Attorney Docket Number	0107262.00184US2	

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
/B1/	AA*	US-6,178,028	01-23-2001	Washiyama et al.		
-	AB*	US-5,798,784	08-25-1998	Nonaka et al.		
	AC*	US-6,288,818	09-11-2001	Yoshimaru et al.		
/BT/	AD*	US-US2002/167583	11-14-2002	Binford et al.		

	FOREIGN PATENT DOCUMENTS						
Exami Initials		Cite No.1	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁶ (If known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁶
/B	T/	ВА	WO-00/02424	01-13-2000	LASER IMAGING SYSTEMS GMBH & CO. KG		
		BB	WO-98/27450	06-25-1998	ETEC SYSTEMS, INC.		
/B	T/	вс	WO-01/71655		LEXMARK INTERNATIONAL, INC.		П

*EXAMINE: Initial reference considered, whether or not dation is a conformance with MEPE DOD. Draw line through classiful rich in conformance and rote considered. Include copy of the form which need communication to applicant. *CTIES No. Those application lives (but he are made with an erigin satering who to the CIEs No. ser not supplied under 37 CFR 1.98(s)(2)(s)) because that application was filled after June 30, 2003 or it evaluable in the PIV. *Application control in the CIES No. ser not supplied (under 37 CFR 1.98(s)(2)(s)) because that application was filled after June 30, 2003 or it evaluable in the PIV. *Application control in the CIES No. *CTIES No. *CTI

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²	
/BT/	CA	European Search Report issued for EP 04 784 504.5, dated January 28, 2008		
/BT/	СВ	Allen, P. C. et al.: "Next-generation DUV ALTA mask patterning capabilities" PROCEEDINGS OF THE SPIE - THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING SPIE-INIT. SOC. OPT. ENG USA, vol. 5567, no. 1, 2004, pages 279-290, XP002450281 ISSN: 0277-766X		

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Examiner Signature	/Brandi Thomas/	Date Considered	06/10/2008
8592107			

¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.